

Approval Sheet

Customer	
Product Number	M4US-2GSV1C0J-E
Module speed	PC4-2400
Pin	288 pin
CI-tRCD-tRP	17-17-17
SDRAM Operating Temp	0℃~95℃
Date	23 rd June 2017

The Total Solution For Industrial Flash Storage



1. Features

Key Parameter

Industry	Speed	Da	ita Rate MT/	s	tRCD	tRP	tRC	
Nomenclature	Grade	CL=13	CL=15	CL=17	(ns)	(ns)	(ns)	
PC4-2400	S	1866	2133	2400	14.16	14.16	46.16	

- JEDEC Standard 288-pin Dual In-Line Memory Module
- Intend for PC4-2400 applications
- Inputs and Outputs are SSTL-12 compatible
- VDD=VDDQ= 1.2 Volt (TYP)
- VPP=2.5 Volt (TYP)
- VDDSPD=2.2-3.6V
- Low-Power auto self-refresh (LPASR)
- SDRAMs have 16 internal banks for concurrent operation (4 Bank Group of 4 banks each)
- Normal and Dynamic On-Die Termination for data, strobe and mask signals.
- Data bus inversion (DBI) for data bus

- Fixed burst chop (BC) of 4 and burst length (BL) of 8 via the MRS
- Selectable BC4 or BL8 on-the fly (OTF)
- Golden Connector
- Fly-By topology
- Terminated control, command and address bus
- Programmable /CAS Latency:
 10,11,12,13,14,15,16,17,18
- Operation temperature Tc (0°C ~95°C)
- On-die VREFDQ generation and Calibration
- On-Board EEPROM
- RoHS and Halogen free (Section 13)



2. Environmental Requirements

DDR4 UDIMMs are intended for use in standard office environments that have limited capacity for heating and air conditioning. (Followed JEDEC)

Symbol	Parameter	Rating	Units	Notes
Topr	Operating Temperature (ambient)	0 to +55	°C	1
Тѕтс	Storage Temperature	-50 to +100	°C	
Hopr	Operating Humidity (relative)	10 to 90	%	
Нѕтс	Storage Humidity (without condensation)	5 to 95	%	
PBAR	Barometric Pressure (operating & storage)	105 to 69	K Pascal	1,2

^{1.} The component maximum case temperature (Tcase) shall not exceed the value specified in the DDR4 DRAM component specification.

3. SDRAM Parameters by device density

RTT_Nom Setting	Paran	4Gb	Units	
ADEE!	Average periodic refresh	0°C≦Tcase≦85°C	7.8	μs
tREFI	interval	85°C< T case ≤95 °C	3.9	μs

^{2.} Up to 9850 ft.



4. Ordering Information

DDR4 UDIMM										
Part Number	Density	Speed	DIMM	Number of	Number	ECC				
r alt Nullibel	Density	Speed	Organization	DRAM	of rank	LCC				
M4US-2GSV1C0J-E	2GB	PC4-2400	256Mx64	4	1	N				



Pin Configurations (Front side/Back side)

DDR4 UDIMM

Pin	Front	Pin	Back	Pin	Front	Pin	Back	Pin	Front	Pin	Back	Pin	Front	Pin	Back
1	NC	145	NC	37	VSS	181	DQ29	73	VDD	217	VDD	109	VSS	253	DQ41
2	VSS	146	VREFCA	38	DQ24	182	VSS	74	CK0_t	218	CK1_t	110	DM5_n/ DBI5_n,NC	254	VSS
3	DQ4	147	vss	39	vss	183	DQ25	75	CK0_c	219	CK1_c	111	NC	255	DQS5
4	VSS	148	DQ5	40	DM3_n/ DBI3_n,NC	184	VSS	76	VDD	220	VDD	112	vss	256	DQS5
5	DQ0	149	VSS	41	NC	185	DQS3_c	77	VTT	221	VTT	113	DQ46	257	VSS
6	vss	150	DQ1	42	VSS	186	DQS3_t	78	EVENT_n,NF	222	PARITY	114	vss	258	DQ4
7	DM0_n_t/ DBI0_n	151	VSS	43	DQ30	187	VSS	79	A0	223	VDD	115	DQ42	259	VSS
8	NC	152	DQS0_c	44	VSS	188	DQ31	80	VDD	224	BA1	116	vss	260	DQ4
9	VSS	153	DQS0_t	45	DQ26	189	VSS	81	BA0	225	A10/AP	117	DQ52	261	VSS
10	DQ6	154	VSS	46	VSS	190	DQ27	82	RAS_n /A16	226	VDD	118	VSS	262	DQ5
11	VSS	155	DQ7	47	CB4/NC	191	VSS	83	VDD	227	NC	119	DQ48	263	VSS
12	DQ2	156	VSS	48	VSS	192	CB5,NC	84	CS0_n	228	WE_n/ A14	120	VSS	264	DQ49
13	VSS	157	DQ3	49	CB0/NC	193	VSS	85	VDD	229	VDD	121	DM6_n/ DBI6_n	265	VSS
14	DQ12	158	VSS	50	VSS	194	CB1,NC	86	CAS_n/ A15	230	NC	122	NC	266	DQS6
15	VSS	159	DQ13	51	DM8_n/ DBI8_n.NC	195	VSS	87	ODT0	231	VDD	123	VSS	267	DQS6
16	DQ8	160	VSS	52	NC	196	DQS8_c	88	VDD	232	A13	124	DQ54	268	VSS
17	VSS	161	DQ9	53	vss	197	DQS8_t	89	CS1_n	233	VDD	125	vss	269	DQ5
18	DMI_n/ DBI1_n,NC	162	vss	54	CB6 DBI8_n,NC	198	VSS	90	VDD	234	NC	126	DQ50	270	VSS
19	NC	163	DQS1_c	55	vss	199	CB7,NC	91	ODT1	235	NC	127	vss	271	DQ5
20	VSS	164	DQS1_t	56	CB2/NC	200	VSS	92	VDD	236	VDD	128	DQ60	272	VSS
21	DQ14	165	vss	57	vss	201	CB3,NC	93	NC	237	NC	129	vss	273	DQ6
22	VSS	166	DQ15	58	RESET_n	202	VSS	94	VSS	238	SA2	130	DQ56	274	VSS
23	DQ10	167	vss	59	VDD	203	CKE1	95	DQ36	239	vss	131	vss	275	DQ57
24	VSS	168	DQ11	60	CKE0	204	VDD	96	VSS	240	DQ37	132	DM7_n/ DBI7_n,NC	276	VSS
25	DQ20	169	VSS	61	VDD	205	NC	97	DQ32	241	VSS	133	NC	277	DQS7
26	VSS	170	DQ21	62	ACT_n	206	VDD	98	VSS	242	DQ33	134	VSS	278	DQS7
27	DQ16	171	VSS	63	BG0	207	BG1	99	DM4_n/ DBI4_n,NC	243	VSS	135	DQ62	279	VSS
28	VSS	172	DQ17	64	VDD	208	ALERT_n	100	NC	244	DQS4_c	136	VSS	280	DQ63
29	DM2_n/ DBI2_n,NC	173	VSS	65	A12/BC_n	209	VDD	101	VSS	245	DQS4_t	137	DQ58	281	VSS
30	NC	174	DQS2_c	66	A9	210	A11	102	DQ38	246	VSS	138	VSS	282	DQ59
31	VSS	175	DQS2_t	67	VDD	211	A7	103	VSS	247	DQ39	139	SA0	283	VSS
32	DQ22	176	VSS	68	A8	212	VDD	104	DQ34	248	VSS	140	SA1	284	VSSSF
33	VSS	177	DQ23	69	A6	213	A5	105	VSS	249	DQ35	141	SCL	285	SDA
34	DQ18	178	VSS	70	VDD	214	A4	106	DQ44	250	VSS	142	VPP	286	VPP
35	VSS	179	DQ19	71	A3	215	VDD	107	VSS	251	DQ45	143	VPP	287	VPP
36	DQ28	180	VSS	72	A1	216	A2	108	DQ40	252	VSS	144	NC	288	VPP

Note:

1. NC = No Connect, RFU = Reserved for Future Use
2. Address A17 is only valid for 16 Gb x4 based SDRAMs.
3. RAS, n is a multiplexed function with A16.
4. CAS, n is a multiplexed function with A15.
5. WE_n is a multiplexed function with A14.
6. CBx is for ECC UDIMM only



6. Architecture

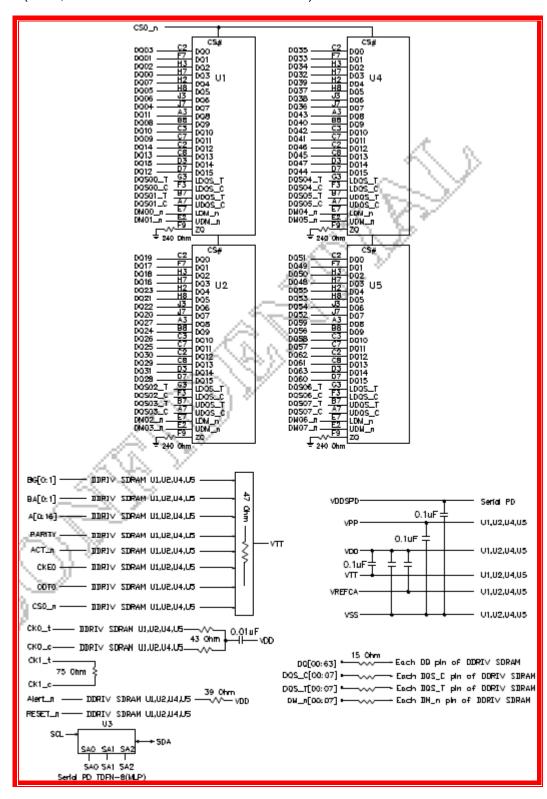
Pin Definition

Pin Name	Description	Pin Name	Description
Ax	SDRAM address bus	SCL	Serial Clock for temperature sensor/SPD EEPROM
A10/AP	Auto-Precharge	DQx, CBx	Data input/output and check bit input/output:
A12/BC_n	Burst Chop	DM_n/ DBI_n/TDQS_t (DMU_n, DBIU_n), (DML_n/DBII_n)	Input data mask and data bus inversion:
ACT_n	Command Input	SDA	Serial Data
BAx	Bank Address Inputs	DQS_t DQS_c DQSU_t DQSU_c DQSL_t DQSL_t	Data strobe:
BGx	Bank Group Address Inputs	ALERT_n	Alert output
C0, C1,C2 (RDIMM or LRDIMM only)	Chip ID	EVENT_n	Temperature event
CKx_t CKx_c	Clock	TDQS_t, TDQS_c (x8 DRAM-based RDIMM only)	Termination data strobe:
CKEx	Clock enable	VDD	Module power supply: 1.20V (TYP)
CSx_n	Chip Select	VPP	DRAM activating power supply: 2.5V – 0.125V / +0.250V
ODTx	On-Die Termination	VREFCA	Reference voltage for control, command, and address pins
Parity	Parity of Command and Address	VSS	Ground
RAS_n/A16 CAS_n/A15 WE_n/A14	Command Input	VIT	Power supply for termination of address, command, and control VDD/2.
RESET_n	Active LOW asynchronous reset	VDDSPD	Power supply used to power the I2C bus for SPD.
SAx	Serial address Input	RFU	Reserved for future use.
NF	No function	NC	No Connect



7. Function Block Diagram:

- (2GB, 1 Rank 256Mx16 DDR4 SDRAMs)



Note: 1. The ZQ ball on each DDR4 component is connected to an external 240 Ω ±1% resistor that is tied to ground. It is used for the calibration of the component's ODT and output driver.



8. SDRAM Absolute Maximum Ratings

Symbol	Pa	arameter	Rating	Units	Note
_	Operation Temperature Normal Operating Temp. Extended Temp.(optional)		0 to 85	°C	1,2
T _{OPER}			85 to 95	°C	1,3
T _{STG}	Storage Temperature		-55 to 100	°C	4,5
V _{IN,} V _{OUT}	Voltage on any pins rela	tive to Vss	-0.3 to +1.5	V	4
V _{DD}	Voltage on VDD supply relative to Vss		-0.3 to +1.5	V	4,6
V _{DDQ}	Voltage on VDDQ suppl	y relative to Vss	-0.3 to +1.5	V	4,6

Note

1. Operating Temperature TOPER is the case surface temperature on the center / top side of the DRAM.

For measurement conditions, please refer to the JEDEC document JESD51-2.

- 2. The Normal Temperature Range specifies the temperatures where all DRAM specifications will be supported. During operation, the DRAM case temperature must be maintained between 0 to 85 °C under all operating conditions.
- 3. Some applications require operation of the DRAM in the Extended Temperature Range between 85 °C and 95 °C case temperature. Full specifications are supported in this range, but the following additional conditions apply:
 - a) Refresh commands must be doubled in frequency, therefore reducing the Refresh interval tREFI to 3.9 μs. It is also possible to specify a component with 1X refresh (tREFI to 7.8μs) in the Extended Temperature Range. Please refer to supplier data sheet and/or the DIMM SPD for option availability.
- b) If Self-Refresh operation is required in the Extended Temperature Range, then it is mandatory to either use the Manual Self-Refresh mode with Extended Temperature Range capability (MR2 A6 =0b and MR2 A7 = 1b) or enable the optional Auto Self-Refresh mode (MR2 A6 = 1b and MR2 A7 =0b). Please refer to the supplier data sheet and/or the DIMM SPD for Auto Self-Refresh option availability, Extended Temperature Range support and tREFI requirements in the Extended Temperature Range.
- 4. Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is stress rating only, and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- 5. Storage Temperature is the case surface temperature on the center/top side of the DRAM. For the measurement conditions, please refer to JESD51-2 standard.
- 6. VDD and VDDQ must be within 300 mV of each other at all times; and VREF must be not greater than 0.6 x VDDQ, When VDD and VDDQ are less than 500 mV; VREF may be equal to or less than 300 mV



9. Module Absolute Maximum Ratings

Symbol	Parameter	Rating	Units	Notes
V _{IN} , V _{OUT}	Voltage on I/O pins relative to Vss	-0.3 to +1.5	V	
V _{DD}	Voltage on VDD supply relative to Vss	-0.3 to +1.5	V	1
V _{DDQ}	Voltage on VDDQ supply relative to Vss	-0.3 to +1.5	V	1
V _{PP}	Voltage on VPP supply relative to Vss	-0.3 to +3.0	V	2

Note:

- 1. VDDQ tracks with VDD; VDDQ and VDD are tied together.
- VPP must be greater than or equal to VDD at all times.



10. Operating Condition

Symbol	Parameter	Min	Nom	Мах	Units	Notes
VDD	Supply Voltage	1.14	1.2	1.26	V	1
VPP	DRAM activating power supply	2.375	2.5	2.75	V	2
VREFCA(DC)	Input reference voltage command/ address bus	0.49 x VDD	0.5 x VDD	0.51 x VDD	V	3
lvtt	Termination reference voltage (DC) – command/address bus	-750	-	750	mA	
Vтт	Termination Voltage	0.49 × VDD	0.5 × VDD	0.51 × VDD	V	4
lı	Input leakage current; any input excluding ZQ; 0V < VIN < 1.1V	-2.0	-	2.0	μΑ	5
II/O	DQ leakage; 0V < Vin < VDD	-4.0	-	4.0	μΑ	5
lOZpd	Output leakage current; VOUT = VDD; DQ is disabled	-	-	5.0	μΑ	5,6
loz _{pu}	Output leakage current; VOUT =VSS; DQ and ODT are disabled; ODT is disabled with ODT input HIGH	VREF + 0.125	-	VDDQ + 0.3	μA	1
lOZpd	VREFCA leakage; VREFCA = VDD/2 (after DRAM is initialized)	-2.0	-	2.0	μΑ	5

Note:

- VDDQ tracks with VDD; VDDQ and VDD are tied together.
- VPP must be greater than or equal to VDD at all times.
- 3. VREFCA must not be greater than 0.6 x VDD. When VDD is less than 500mV, VREF may be less than or equal to
- VTT termination voltages in excess of the specification limit adversely affect the voltage margins of command and address signals and reduce timing margins.
- 5. Multiply by the number of DRAM die on the module.
- Tied to ground. Not connected to edge connector.



11. Operating, Standby, and Refresh Currents

- 2GB UDIMM (1 Rank 265Mx16 DDR4 SDRAMs)

County of	December 1 Completions	Va	lue	l luite
Symbol	Proposed Conditions	IDD Max.	IPP Max.	Units
	Operating One Bank Active-Precharge Current (AL=0)CKE: High; External clock: On; tCK,			
	nRC, nRAS, CL: Refer to Component Datasheet for detail pattern; BL: 81; AL: 0; CS_n:			
	Highbetween ACT and PRE; Command, Address, Bank Group Address, Bank Address			
IDD0	Inputs: partially toggling; Data IO: VDDQ; DM_n:stable at 1; Bank Activity: Cycling with one	140	16	mA
	bank active at a time: 0,0,1,1,2,2,; Output Buffer and RTT: Enabled in Mode			
	Registers2;ODT Signal: stable at 0; Pattern Details: Refer to Component Datasheet for			
	detail pattern			
IDDOA	Operating One Bank Active-Precharge Current (AL=CL-1)	4.40	40	
IDD0A	AL = CL-1, Other conditions: see IDD0	148	16	mA
	Operating One Bank Active-Read-Precharge Current (AL=0)CKE: High;		16	
	External clock: On; tCK, nRC, nRAS, nRCD, CL: Refer to Component			
	Datasheet for detail pattern; BL: 81; AL: 0; CS_n: Highbetween ACT, RD and			
IDD.	PRE; Command, Address, Bank Group Address, Bank Address Inputs, Data	040		٥
IDD1	IO: partially toggling; DM_n: stableat 1; Bank Activity: Cycling with one bank	212		mA
	active at a time: 0,0,1,1,2,2,; Output Buffer and RTT: Enabled in Mode			
	Registers2; ODT Signal: stable at 0; Pattern Details: Refer to Component			
	Datasheet for detail pattern			
IDDAA	Operating One Bank Active-Read-Precharge Current (AL=CL-1)	004	40	0
IDD1A	AL = CL-1, Other conditions: see IDD1	224	16	mA
	Precharge Standby Current (AL=0)CKE: High; External clock: On; tCK, CL:			
	Refer to Component Datasheet for detail pattern; BL: 81; AL: 0; CS_n: stable at			
IDDON	1; Command,Address, Bank Group Address, Bank Address Inputs: partially	00	40	A
IDD2N	toggling; Data IO: VDDQ; DM_n: stable at 1; Bank Activity: all banksclosed;	60	12	mA
	Output Buffer and RTT: Enabled in Mode Registers2; ODT Signal: stable at 0;			
	Pattern Details: Refer to Component Datasheet for detail pattern			
IDDONA	Precharge Standby Current (AL=CL-1)	70	40	
IDD2NA	AL = CL-1, Other conditions: see IDD2N	72	12	mA



	Precharge Standby ODT Current			
	CKE: High; External clock: On; tCK, CL: Refer to Component Datasheet for			
	detail pattern; BL: 81; AL: 0; CS_n: stable at 1; Command, Address, Bank			mA
IDD2NT	Group Address, Bank Address Inputs: partially toggling; Data IO: VSSQ;	64	12	
	DM_n: stable at 1; Bank Activity: all banks closed; Output Buffer and RTT:			
	Enabled in Mode Registers2; ODT Signal: toggling according; Pattern Details:			
	Refer to Component Datasheet for detail pattern			
IDD2NL	Precharge Standby Current with CAL enabled	44	12	mA
IDDZINE	Same definition like for IDD2N, CAL enabled3	44	12	ША
IDDONO	Precharge Standby Current with Gear Down mode enabled	60	40	A
IDD2NG	Same definition like for IDD2N, Gear Down mode enabled3	60	12	mA
IDD 61 ID	Precharge Standby Current with DLL disabled	40	40	
IDD2ND	Same definition like for IDD2N, DLL disabled3	48	12	mA
	Precharge Standby Current with CA parity enabled			
IDD2N_par	Same definition like for IDD2N, CA parity enabled3	60	12	mA
	Precharge Power-Down Current CKE: Low; External clock: On; tCK, CL: Refer		12	
	to Component Datasheet for detail pattern; BL: 81; AL:0; CS_n: stable at 1;	40		
	Command, Address, Bank Group Address, Bank Address Inputs: stable at 0;			_
IDD2P	Data IO: VDDQ; DM_n: stable at 1;			mA
	Bank Activity: all banks closed; Output Buffer and RTT: Enabled in Mode			
	Registers2; ODT Signal: stable at 0			
	Precharge Quiet Standby Current			
	CKE: High; External clock: On; tCK, CL: Refer to Component Datasheet for			
	detail pattern; BL: 81; AL: 0; CS_n: stable at 1; Command,			
IDD2Q	Address, Bank Group Address, Bank Address Inputs: stable at 0; Data IO:	52	12	mA
	VDDQ; DM_n: stable at 1;Bank Activity: all banks closed;			
	Output Buffer and RTT: Enabled in Mode Registers2; ODT Signal: stable at 0			
	Active Standby Current			
	CKE: High; External clock: On; tCK, CL: Refer to Component Datasheet for			
	detail pattern; BL: 81; AL: 0; CS_n: stable at 1; Command,			
	Address, Bank Group Address, Bank Address Inputs: partially toggling; Data			
IDD3N	IO: VDDQ; DM_n: stable at 1;Bank Activity: all banks	108	12	mA
	open; Output Buffer and RTT: Enabled in Mode Registers2; ODT Signal: stable			
	at 0; Pattern Details:Refer to Component Datasheet			
	for detail pattern			
	Tor dotain pattorn			



	Active Standby Current (AL=CL-1)			
IDD3NA	AL = CL-1, Other conditions: see IDD3N	112	12	mA
	Active Power-Down Current			
IDD3P	CKE: Low; External clock: On; tCK, CL: sRefer to Component Datasheet for		12	mA
	detail pattern; BL: 81; AL: 0; CS_n: stable at 1; Command,			
	Address, Bank Group Address, Bank Address Inputs: stable at 0; Data IO:	52		
	VDDQ; DM_n: stable at 1; Bank Activity: all banks open;			
	Output Buffer and RTT: Enabled in Mode Registers2; ODT Signal: stable at 0			
	Operating Burst Read Current			
	CKE: High; External clock: On; tCK, CL: Refer to Component Datasheet for		12	mA
	detail pattern; BL: 82; AL: 0; CS_n: High between RD;			
	Command, Address, Bank Group Address, Bank Address Inputs: partially			
	toggling; Data IO: seamless read data burst with different			
IDD4R	data between one burst and the next one according; DM_n: stable at 1; Bank	516		
	Activity: all banks open, RD commands cycling through			
	banks: 0,0,1,1,2,2,; Output Buffer and RTT: Enabled in Mode Registers2;			
	ODT Signal: stable at 0; Pattern Details: Refer to			
	Component Datasheet for detail pattern			
	Operating Burst Read Current (AL=CL-1)			
IDD4RA	AL = CL-1, Other conditions: see IDD4R	532	12	mA
	Operating Burst Read Current with Read DBI		12	mA
IDD4RB	Read DBI enabled3, Other conditions: see IDD4R	532		
	Operating Burst Write Current		12	mA
	CKE: High; External clock: On; tCK, CL: Refer to Component Datasheet for			
	detail pattern; BL: 81; AL: 0; CS_n: High between WR;			
	Command, Address, Bank Group Address, Bank Address Inputs: partially			
	toggling ; Data IO: seamless write data burst with different	344		
IDD4W	data between one burst and the next one; DM_n: stable at 1; Bank Activity: all			
	banks open, WR commands cycling through banks:			
	0,0,1,1,2,2,; Output Buffer and RTT: Enabled in Mode Registers2; ODT			
	Signal: stable at HIGH; Pattern Details: Refer to Component			
	Datasheet for detail pattern			
IDD	Operating Burst Write Current (AL=CL-1)	105	40	mA
IDD4WA	AL = CL-1, Other conditions: see IDD4W	400	12	
IDD 4445	Operating Burst Write Current with Write DBI	65.	12	mA
IDD4WB	Write DBI enabled3, Other conditions: see IDD4W	384		



Operating Burst Write Current with Write CRC IDD4WC Write CRC enabled3, Other conditions: see IDD4W 332 12	mA
	1117
<u> </u>	
Operating Burst Write Current with CA Parity IDD4W_par 412 12	mA
CA Parity enabled3, Other conditions: see IDD4W	, \
Burst Refresh Current (1X REF)	
CKE: High; External clock: On; tCK, CL, nRFC: Refer to Component Datasheet	
for detail pattern; BL: 81; AL: 0; CS_n: High between	
REF; Command, Address, Bank Group Address, Bank Address Inputs: partially 10058 780 76	mA
toggling ; Data IO: VDDQ; DM_n: stable at 1; Bank	ША
Activity: REF command every nRFC ; Output Buffer and RTT: Enabled in Mode	
Registers2; ODT Signal: stable at 0; Pattern Details:	
Refer to Component Datasheet for detail pattern	
Burst Refresh Current (2X REF)	
IDD5F2 640 64 tRFC=tRFC_x2, Other conditions: see IDD5B	mA
Burst Refresh Current (4X REF) 480 48	~~ ∧
IDD5F4 480 48 tRFC=tRFC_x4, Other conditions: see IDD5B	mA
Self Refresh Current: Normal Temperature Range	
TCASE: 0 - 85°C; Low Power Array Self Refresh (LP ASR) : Normal4; CKE:	mA
Low; External clock: Off; CK_t and CK_c#: LOW; CL: Refer	
IDD6N to Component Datasheet for detail pattern; BL: 81; AL: 0; CS_n#, Command, 52 16	
Address, Bank Group Address, Bank Address, Data IO:	
High; DM_n: stable at 1; Bank Activity: Self-Refresh operation; Output Buffer	
and RTT: Enabled in Mode Registers2; ODT Signal: MIDLEVEL	
Self-Refresh Current: Extended Temperature Range)	
TCASE: 0 - 95°C; Low Power Array Self Refresh (LP ASR) : Extended4; CKE:	
Low; External clock: Off; CK_t and CK_c: LOW; CL:	
Refer to Component Datasheet for detail pattern; BL: 81; AL: 0; CS_n,	4
IDD6E Command, Address, Bank Group Address, Bank Address, Data	mA
IO: High; DM_n:stable at 1; Bank Activity: Extended Temperature Self-Refresh	
operation; Output Buffer and RTT: Enabled in Mode	
Registers2; ODT Signal: MID-LEVEL	

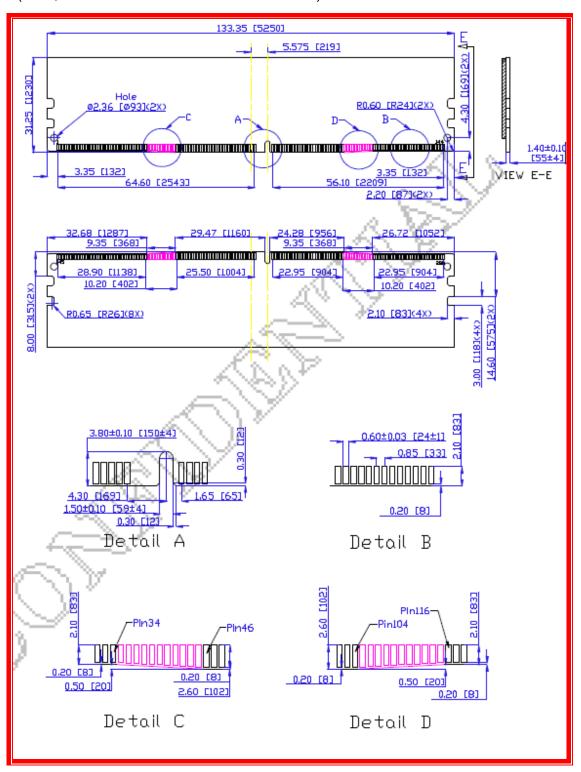


	Self-Refresh Current: Reduced Temperature Range			
IDD6R	TCASE: 0 - TBD (~35-45)°C; Low Power Array Self Refresh (LP ASR) :		16	mA
	Reduced4; CKE: Low; External clock: Off; CK_t and CK_c#: LOW;			
	CL: Refer to Component Datasheet for detail pattern; BL: 81; AL: 0; CS_n#,	40		
	Command, Address, Bank Group Address, Bank Address,	40		
	Data IO: High; DM_n:stable at 1; Bank Activity: Extended Temperature			
	Self-Refresh operation; Output Buffer and RTT: Enabled in Mode			
	Registers2; ODT Signal: MID-LEVEL			
	Auto Self-Refresh Current			
	TCASE: 0 - 95°C; Low Power Array Self Refresh (LP ASR) : Auto4;Partial Array	52		mA
	Self-Refresh (PASR): Full Array; CKE: Low; External			
IDDev	clock: Off; CK_t and CK_c#: LOW; CL: Refer to Component Datasheet for		16	
IDD6A	detail pattern; BL: 81; AL: 0; CS_n#, Command, Address, Bank		16	
	Group Address, Bank Address, Data IO: High; DM_n:stable at 1; Bank Activity:			
	Auto Self-Refresh operation; Output Buffer and RTT:			
	Enabled in Mode Registers2; ODT Signal: MID-LEVEL			
	Operating Bank Interleave Read Current			
	CKE: High; External clock: On; tCK, nRC, nRAS, nRCD, nRRD, nFAW, CL:		48	mA
	Refer to Component Datasheet for detail pattern; BL: 81; AL:			
	CL-1; CS_n: High between ACT and RDA; Command, Address, Bank Group	744		
IDD7	Address, Bank Address Inputs: partially toggling; DataIO: read data bursts with			
	different data between one burst and the next one; DM_n: stable at 1; Bank			
	Activity: two times interleaved cycling			
	through banks (0, 1,7) with different addressing; Output Buffer and RTT:			
	Enabled in Mode Registers2; ODT Signal: stable at 0; Pattern			
	Details: Refer to Component Datasheet for detail pattern			
IDD8	Maximum Power Down Current TBD	26	8	mA



12. PACKAGE DIMENSION

- (2GB, 1 Rank 256x16 DDR4 base UDIMM)



Note: All dimensions are in millimeters (mils) and should be kept within a tolerance of ± 0.15 (6), unless otherwise specified.



13. RoHS Declaration

innodisk

宜鼎國際股份有限公司

Page 1/1

Innodisk Corporation

Tel:(02)7703-3000 Fax:(02) 7703-3555 Internet: http://www.innodisk.com/

ROHS 自我宣告書(RoHS Declaration of Conformity)

Manufacturer Product: All Innodisk EM Flash and Dram products

一、 宜鼎國際股份有限公司(以下稱本公司)特此保證修予責公司之所有產品,皆符合歐盟 2011/65/EU關於 RoHS 之規範要求。

Innodisk Corporation declares that all products sold to the company, are complied with European Union RoHS Directive (2011/65/EU) requirement.

二、 本公司同意因本保證書或與本保證書相關事宣有所爭議時,雙方宣友好協商,達成協議。

Innodisk Corporation agrees that both parties shall settle any dispute arising from or in connection with this Declaration of Conformity by friendly negotiations.

Name of hazardous substance	Limited of RoHS ppm (mg/kg)		
鉛 (Pb)	< 1000 ppm		
乘 (Hg)	< 1000 ppm		
鍋 (Cd)	< 100 ppm		
六價鉻 (Cr 6+)	< 1000 ppm		
多溴聯苯 (PBBs)	< 1000 ppm		
多溴二苯醚 (PBDEs)	< 1000 ppm		

立 保 證 🛊 人 (Guarantor)

Company name 公司名稱: Innodisk Corporation 宜鼎國際股份有限公司

Company Representative 公司代表人: Randy Chien 類川勝

Company Representative Title 公司代表人職稱: Chairman 董事長







Revision Log

Rev	Date	Modification
0.1	23 rd June 2017	Preliminary Edition
1.0	23 rd June 2017	Official Released